

### **100V N-Channel Enhancement Mode MOSFET**

#### Description

The AP80N10P/T uses advanced APM-SGTIItechnology

to provide excellent RDS(ON), low gate charge and

operation with gate voltages as low as 10V. This

device is suitable for use as a Battery protection

or in other Switching application.

#### **General Features**

V<sub>DS</sub> = 100V I<sub>D</sub> =80A

R<sub>DS(ON)</sub> < 12mΩ @ V<sub>GS</sub>=10V (Type: 8.0mΩ)

#### Application

Isolated DC

Motor control

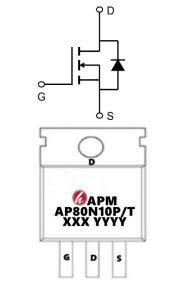
Synchronous-rectification

#### Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)	
AP80N10P	TO-220-3L	AP80N10P XXX YYYY	1000	
AP80N10T	TO-263-3L	AP80N10T XXX YYYY	800	

#### Absolute Maximum Ratings (Tc=25°Cunless otherwise noted)

Symbol	Parameter	Value	Unit
VDS	Drain source voltage	100	V
VGS	Gate source voltage	±20	V
ID	Continuous drain current, TC=25°C	80	А
IDM	Pulsed drain current, TC=25 °C	210	А
PD	Power dissipation, TC=25 °C	107	W
EAS	Single pulsed avalanche energy4)	183.8	mJ
Tstg, Tj	Operation and storage temperature	-55 to 150	°C
RθJC	Thermal resistance, junction-case	1.17	°C/W
RθJA	Thermal resistance, junction-ambient4)	62	°C/W



TO-263 **TO-220** D<sup>2</sup>PAK G D C D S

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#### Electrical Characteristics (Tc=25°C unless otherwise noted)

Symbol	Parameter	Test condition	Min.	Тур.	Max.	Unit
BVDSS	Drain-source breakdown voltage	V <sub>GS</sub> =0 V, I <sub>D</sub> =250 µA	100	111		V
VGS(th)	Gate threshold voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250 µA	2.0	3.0	4.0	V
RDS(ON)	Drain-source on-state resistance	V <sub>GS</sub> =10 V, I <sub>D</sub> =20 A		8	12.0	mΩ
RDS(ON)	Drain-source on-state resistance	V <sub>GS</sub> =4.5 V, I <sub>D</sub> =12 A		12	14.0	mΩ
IGSS	Gate-source leakage current	V <sub>GS</sub> =±20 V			±100	nA
IDSS	Drain-source leakage current	V <sub>DS</sub> =100 V, V <sub>GS</sub> =0 V			1	uA
R <sub>G</sub>	Gate resistance	f= 1 MHz, Open drain		5.5		Ω
Ciss	Input capacitance			1998.1		pF
Coss	Output capacitance	V <sub>GS</sub> =0 V, V <sub>DS</sub> =50 V, f=100 kHz		321.7		pF
Crss	Reverse transfer capacitance			7.1		pF
td(on)	Turn-on delay time	V <sub>GS</sub> =10 V,		22.1		ns
tr	Rise time	V <sub>DS</sub> =50 V,		5.2		ns
td(off)	Turn-off delay time	R <sub>G</sub> =2 Ω,		44		ns
t <sub>f</sub>	Fall time	I <sub>D</sub> =25 A		8.4		ns
Qg	Total gate charge			28.9		nC
Qgs	Gate-source charge	I <sub>D</sub> =25 A,		6		nC
Qgd	Gate-drain charge	- V <sub>DS</sub> =50 V, V <sub>GS</sub> =10 V		6.8		nC
Vplateau	Gate plateau voltage			3.7		V
ls	Diode forward current	VGS <vth< td=""><td></td><td>60</td><td>Α</td></vth<>			60	Α
ISP	Pulsed source current				180	
VSD	Diode forward voltage	Is=20 A, V <sub>GS</sub> =0 V			1.3	V
trr	Reverse recovery time			102.9		ns
Qrr	Reverse recovery charge	I <sub>S</sub> =25 A, di/dt=100 A/µs		379		nC
Irrm	Peak reverse recovery current			6.4		Α

Note :

1、The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.

2. The data tested by pulsed , pulse width  $\,\leq\,$  300us , duty cycle  $\,\leq\,$  2%

3、The EAS data shows Max. rating . The test condition is VDD=30V,VGS=10V, L=0.3mH, starting Tj=25°C

4. The power dissipation is limited by  $150\,^\circ$ C junction temperature

5. The data is theoretically the same as I D and I DM , in real applications , should be limited by total power dissipation

AP80N10P/T RVE1.0

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### **Typical Characteristics**

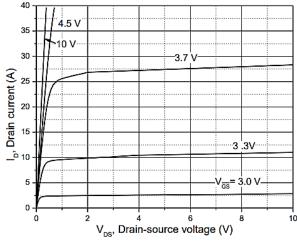


Figure 1. Typ. output characteristics

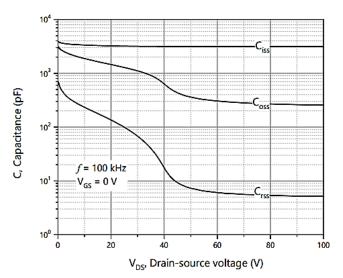


Figure 3. Typ. capacitances

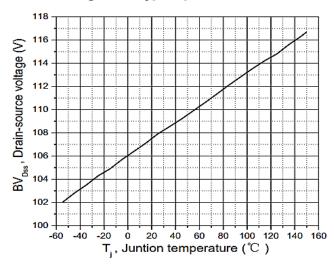


Figure 5. Drain-source breakdown voltage

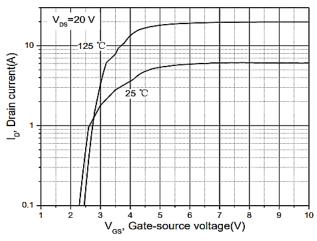


Figure 2. Typ. transfer characteristics

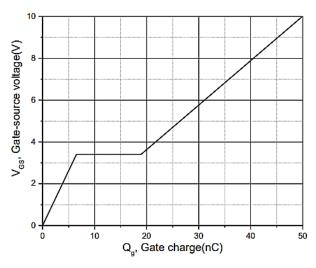


Figure 4. Typ. gate charge

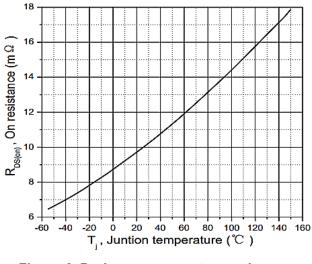


Figure 6. Drain-source on-state resistance

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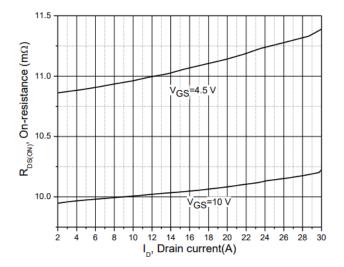


Figure 7. Drain-source on-state resistance

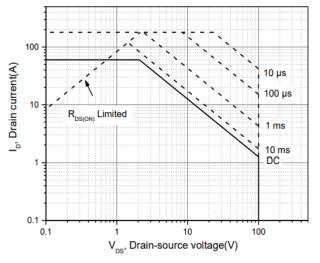


Figure 9. Safe operation area Tc=25 ℃

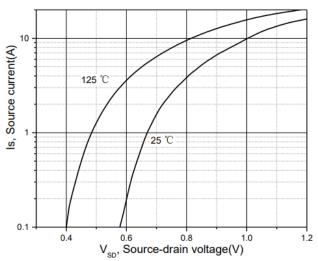
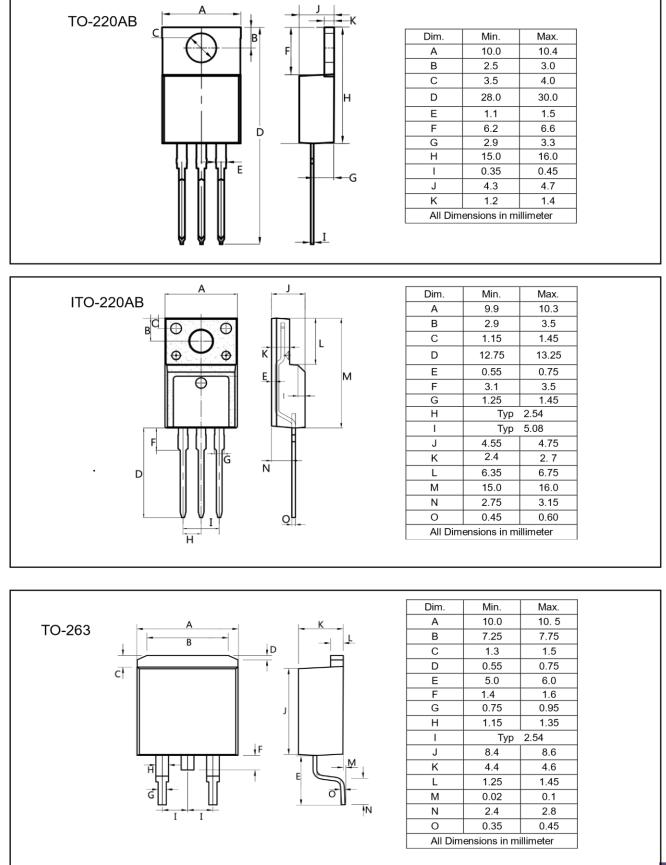


Figure 8. Forward characteristic of body diode

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### **100V N-Channel Enhancement Mode MOSFET**

Edition	Date	Change
Rve1.0	2018/1/31	Initial release

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